

Search Notes

Application/Control No.

10/821,486

Examiner

TAN TRINH

Applicant(s)/Patent under
Reexamination

LAI, YHEAN-SEN

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	3.02	6/27/2007	TT
	12.1		
	562.1		
	13.3		
	142		
	313		
	324		
	323		
370	347		
	389		
375	326		
	344		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/27/2000	